

# **E-PHEMT** Transistor

### TAV1-551+

Mini-Circuits

### 50Ω 0.045 to 6 GHz

### THE BIG DEAL

- Low Noise Figure, 0.5 dB typ. at 0.9 GHz
- Gain, 20.9 dB typ. at 0.9 GHz
- High Output IP3, +24 dBm at 2 GHz, 4V
- Output Power at 1dB compression, +20dBm, 4V
- Wide bandwidth
- External biasing and matching required



Generic photo used for illustration purposes only

CASE STYLE: TE2769

+RoHS Compliant The +Suffix identifies RoHS Compliance. See our web site for RoHS Compliance methodologies and qualifications

### **APPLICATIONS**

- Cellular
- ISM
- GSM
- WCDMA
- WiMax
- WLAN
- UNII and HIPERLAN

### **PRODUCT OVERVIEW**

TAV1-551+ is a low noise, high gain device manufactured using E-PHEMPT\* technology enabling it to work with a single positive supply voltage. It has outstanding Noise figure, particularly below 2.5 GHz, and when combining this noise figure with gain in a single device it makes it an ideal amplifier for multiple applications.

#### **KEY FEATURES**

Feature	Advantages	
Wideband, 0.045 to 6 GHz	Use in multiple applications: UHF, VHF, communication infrastructure	
High Gain, Low noise figure	High Gain limits the effect of noise figure due to previous stages	
Small size, 1.18 x 1.42 x 0.85 mm, MCLP package	Small foot print saves space in dense layouts while providing low inductance, repeatable transitions, and excellent thermal contact to the PCB.	

\* Enhancement mode Pseudomorphic High Electron Mobility Transistor.

REV. A ECO-011337 TAV1-551+ MCL NY 220111



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### **TAV1-551+**

### ELECTRICAL SPECIFICATIONS AT T<sub>AMB</sub>=25°C, FREQUENCY 0.045 TO 6 GHZ

Symbol	Parameter	Conditio	on	Min.	Тур.	Max.	Units
		DC Sr	pecifications				
V <sub>GS</sub>	Operational Gate Voltage	V <sub>DS</sub> =3V, I <sub>DS</sub> =15 mA		0.22	0.34	0.46	V
$V_{TH}$	Threshold Voltage	$V_{DS}$ =3V, $I_{DS}$ =4 mA		0.18	0.26	0.38	V
I <sub>DSS</sub>	Saturated Drain Current	V <sub>DS</sub> =3V, V <sub>GS</sub> =0 V		_	1.0	5.0	uA
G <sub>M</sub>	Transconductance	$ \begin{array}{c} V_{_{DS}} = \!$		215	251	285	mS
I <sub>GSS</sub>	Gate leakage Current	V <sub>GD</sub> =V <sub>GS</sub> =-3V		_	—	95	μA
		RF Specifications <sup>1</sup>	, Z0=50 Ohms (Figure	21)			
		V <sub>DS</sub> =3V, I <sub>DS</sub> =15 mA	f=0.9 GHz		0.5		
NF <sup>1</sup>			f=2.0 GHz	_	0.6	0.9	
	Noise Figure		f=3.9 GHz		0.8		dB
			f=5.8 GHz		1.4		
		$V_{\rm DS}$ =4V, $I_{\rm DS}$ =15 mA	f=2.0 GHz		0.6		
		$V_{\rm DS}$ =3V, $I_{\rm DS}$ =15 mA	f=0.9 GHz		21.6		
			f=2.0 GHz	14.4	16.7	18.4	
Gain	Gain		f=3.9 GHz		11.9		dB
			f=5.8 GHz		8.6		
		$V_{\rm DS}$ =4V, $I_{\rm DS}$ =15 mA	f=2.0 GHz		16.7		
		V <sub>DS</sub> =3V, I <sub>DS</sub> =15 mA	f=0.9 GHz		23.9		
	Output IP3		f=2.0 GHz	20	24.5	-	
OIP3			f=3.9 GHz		24.4		dBm
			f=5.8 GHz		26.0		
		$V_{\rm DS}$ =4V, $I_{\rm DS}$ =15 mA	f=2.0 GHz		24.5		
		V <sub>DS</sub> =3V, I <sub>DS</sub> =15 mA	f=0.9 GHz		16.0		
			f=2.0 GHz	16	17.4	-	
P1dB <sup>2</sup>	Power output at 1 dB Compression		f=3.9 GHz		18.4		dBm
			f=5.8 GHz		18.8		
		$V_{DS}$ =4V, $I_{DS}$ =15 mA	f=2.0 GHz		19.8		



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#### **MAXIMUM RATINGS<sup>3</sup>**

Symbol	Parameter	Max.	Units	
V <sub>DS</sub> <sup>(4)</sup>	Drain-Source Voltage	5	V	
V <sub>GS</sub> <sup>(4)</sup>	Gate-Source Voltage	-5 to 0.7	V	
V <sub>GD</sub> <sup>(4)</sup>	Gate-Drain Voltage	-5 to 0.7	V	
I <sub>DS</sub> <sup>(4)</sup>	Drain Current	100	mA	
lcs	Gate Current	2	mA	
P <sub>DISS</sub>	Total Dissipated Power	360	mW	
P <sub>IN</sub> <sup>(5)</sup>	RF Input Power	17	dBm	
Т <sub>сн</sub>	Channel Temperature	150	°C	
T <sub>op</sub>	Operating Temperature	-40 to 85	°C	
T <sub>STD</sub>	Storage Temperature	-65 to 150	°C	
Θ <sub>JC</sub>	Thermal Resistance	160	°C/W	

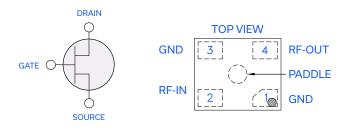
1. Includes test board loss (tested on Mini-Circuits TB-TAV1-551+ test board.

2. Drain current bias is allowed to increase during compression measurement.

3. Operation of this device above any one of these parameters may cause permanent damage

4. Assumes DC quiescent conditions 5.  $I_{GS}$  is limited to 2 mA during test.

#### SIMPLIFIED SCHEMATIC AND PIN DESCRIPTION



Function	Pin Number	Description
RF-IN	2	Gate used for RF input
RF-OUT	4	Drain used for RF output
GND	1,3 and Paddle	Source terminal and Paddle, normally connected to ground.

A. Note: Suitability for model replacement within a particular system must be determined by and is solely the responsibility of the customer based on, among other things, electrical performance criteria, stimulus conditions, and application, compatibility with other components and environmental conditions and stresses B. The Broadcom ATF-331M4 part number is used for identification and comparison purposes only.



# **E-PHEMT** Transistor

### **CHARACTERIZATION TEST CIRCUIT**

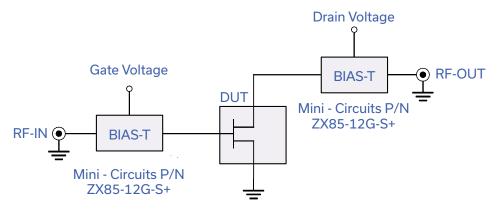


Fig 1. Block Diagram of Test Circuit used for characterization. (DUT soldered on Mini-Circuits Test Board TB-TAV1-551+)

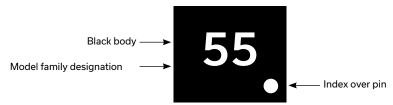
Gain, Output power at 1dB compression (P1 dB), Noise Figure and output IP3 (OIP3) are measured using Keysight/Agilent Network Analyzer PNA-X.

Conditions:

- 1. Drain voltage (with reference to source, VDS)= 3 or 4V as shown.
- 2. Gate Voltage (with reference to source, VGS) is set to obtain desired Drain-Source current (IDS) as shown in specification table.
- 3. Gain: Pin= -25dBm
- 4. Output IP3 (OIP3): Two tones, spaced 1 MHz apart, 0 dBm/tone at output.

5. No external matching components used.

### **PRODUCT MARKING**



Marking may contain other features or characters for internal lot control



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### ADDITIONAL DETAILED TECHNICAL INFORMATION IS AVAILABLE ON OUR DASH BOARD. TO ACCESS CLICK HERE

Performance Data	Data Table Swept Graphs S-Parameter (S2P Files) Data Set (.zip file)
Case Style	TE2769 Plastic package, exposed paddle, lead finish: Matte-Tin plated
Tape & Reel Standard quantities available on reel	F90 7″ reels with 20, 50, 100, 200, 500,1K,2K or 3K devices
Suggested Layout for PCB Design	98-PL-665
Evaluation Board	TB-TAV1-551+
Environmental Ratings	ENV08T2

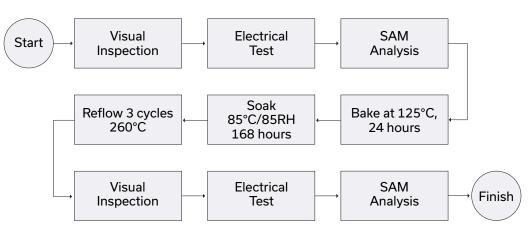
#### **ESD RATING**

Human Body Model (HBM): Class 1A (250V to <500V) in accordance with ANSI/ESD STM 5.1 - 2001

### **MSL RATING**

Moisture Sensitivity: MSL1 in accordance with IPC/JEDEC J-STD-020D

### **MSL TEST FLOW CHART**



#### NOTES

- A. Performance and quality attributes and conditions not expressly stated in this specification document are intended to be excluded and do not form a part of this specification document.
- B. Electrical specifications and performance data contained in this specification document are based on Mini-Circuit's applicable established test performance criteria and measurement instructions.
- C. The parts covered by this specification document are subject to Mini-Circuits standard limited warranty and terms and conditions (collectively, "Standard Terms"); Purchasers of this part are entitled to the rights and benefits contained therein. For a full statement of the standard. Terms and the exclusive rights and remedies thereunder, please visit Mini-Circuits' website at www.minicircuits.com/MCLStore/terms.jsp

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